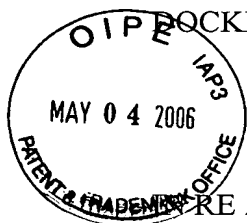


IFW



POCKET NO.: 261137US6YAPCT/phh

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RE APPLICATION OF:

Lee CHEN, et al.

SERIAL NO: 10/517,764

GROUP: 1763

FILED: December 23, 2004

EXAMINER: Allan W. OLSEN

FOR: ANISOTROPIC DRY ETCHING OF CU-CONTAINING LAYERS

LETTER

Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Submitted herewith is an International Preliminary Examination Report for the Examiner's consideration. The reference listed therein has been cited in the Office Action dated March 21, 2006.

Respectfully Submitted,

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